

Search Notes

Application/Control No.

10/632,552

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E27.161, 686 & 777	6/26/2006	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	6/26/2006	C.C.